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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	4704
Number of Logic Elements/Cells	21168
Total RAM Bits	114688
Number of I/O	316
Number of Gates	888439
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	432-LBGA Exposed Pad, Metal
Supplier Device Package	432-MBGA (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv800-4bg432i



Virtex™ 2.5 V Field Programmable Gate Arrays

DS003-2 (v4.0) March 1, 2013

Product Specification

Architectural Description

Virtex Array

The Virtex user-programmable gate array, shown in [Figure 1](#), comprises two major configurable elements: configurable logic blocks (CLBs) and input/output blocks (IOBs).

- CLBs provide the functional elements for constructing logic
- IOBs provide the interface between the package pins and the CLBs

CLBs interconnect through a general routing matrix (GRM). The GRM comprises an array of routing switches located at the intersections of horizontal and vertical routing channels. Each CLB nests into a VersaBlock™ that also provides local routing resources to connect the CLB to the GRM.

The VersaRing™ I/O interface provides additional routing resources around the periphery of the device. This routing improves I/O routability and facilitates pin locking.

The Virtex architecture also includes the following circuits that connect to the GRM.

- Dedicated block memories of 4096 bits each
- Clock DLLs for clock-distribution delay compensation and clock domain control
- 3-State buffers (BUFTs) associated with each CLB that drive dedicated segmentable horizontal routing resources

Values stored in static memory cells control the configurable logic elements and interconnect resources. These values load into the memory cells on power-up, and can reload if necessary to change the function of the device.

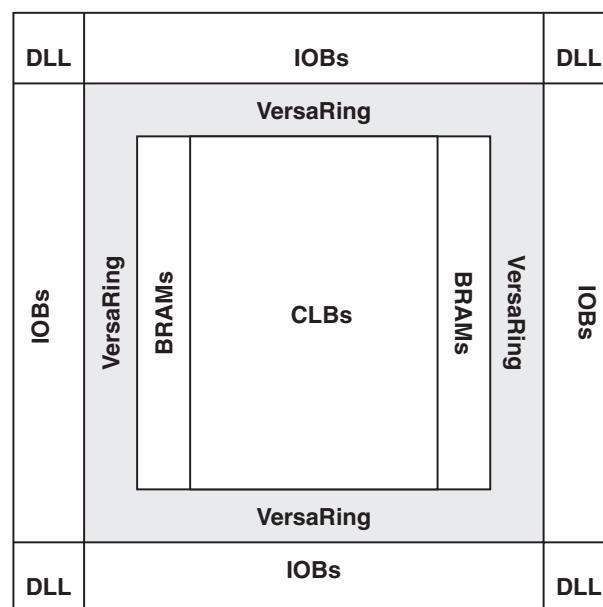
Input/Output Block

The Virtex IOB, [Figure 2](#), features SelectIO™ inputs and outputs that support a wide variety of I/O signalling standards, see [Table 1](#).

The three IOB storage elements function either as edge-triggered D-type flip-flops or as level sensitive latches. Each IOB has a clock signal (CLK) shared by the three flip-flops and independent clock enable signals for each flip-flop.

In addition to the CLK and CE control signals, the three flip-flops share a Set/Reset (SR). For each flip-flop, this signal can be independently configured as a synchronous Set, a synchronous Reset, an asynchronous Preset, or an asynchronous Clear.

The output buffer and all of the IOB control signals have independent polarity controls.



vao_b.eps

Figure 1: Virtex Architecture Overview

All pads are protected against damage from electrostatic discharge (ESD) and from over-voltage transients. Two forms of over-voltage protection are provided, one that permits 5 V compliance, and one that does not. For 5 V compliance, a Zener-like structure connected to ground turns on when the output rises to approximately 6.5 V. When PCI 3.3 V compliance is required, a conventional clamp diode is connected to the output supply voltage, V_{CCO} .

Optional pull-up and pull-down resistors and an optional weak-keeper circuit are attached to each pad. Prior to configuration, all pins not involved in configuration are forced into their high-impedance state. The pull-down resistors and the weak-keeper circuits are inactive, but inputs can optionally be pulled up.

The activation of pull-up resistors prior to configuration is controlled on a global basis by the configuration mode pins. If the pull-up resistors are not activated, all the pins will float. Consequently, external pull-up or pull-down resistors must be provided on pins required to be at a well-defined logic level prior to configuration.

All Virtex IOBs support IEEE 1149.1-compatible boundary scan testing.

more I/O pins convert to V_{REF} pins. Since these are always a superset of the V_{REF} pins used for smaller devices, it is possible to design a PCB that permits migration to a larger device if necessary. All the V_{REF} pins for the largest device anticipated must be connected to the V_{REF} voltage, and not used for I/O.

In smaller devices, some V_{CCO} pins used in larger devices do not connect within the package. These unconnected pins can be left unconnected externally, or can be connected to the V_{CCO} voltage to permit migration to a larger device if necessary.

In TQ144 and PQ/HQ240 packages, all V_{CCO} pins are bonded together internally, and consequently the same V_{CCO} voltage must be connected to all of them. In the CS144 package, bank pairs that share a side are interconnected internally, permitting four choices for V_{CCO} . In both cases, the V_{REF} pins remain internally connected as eight banks, and can be used as described previously.

Configurable Logic Block

The basic building block of the Virtex CLB is the logic cell (LC). An LC includes a 4-input function generator, carry logic, and a storage element. The output from the function generator in each LC drives both the CLB output and the D input of the flip-flop. Each Virtex CLB contains four LCs, organized in two similar slices, as shown in Figure 4.

Figure 5 shows a more detailed view of a single slice.

In addition to the four basic LCs, the Virtex CLB contains logic that combines function generators to provide functions

of five or six inputs. Consequently, when estimating the number of system gates provided by a given device, each CLB counts as 4.5 LCs.

Look-Up Tables

Virtex function generators are implemented as 4-input look-up tables (LUTs). In addition to operating as a function generator, each LUT can provide a 16 x 1-bit synchronous RAM. Furthermore, the two LUTs within a slice can be combined to create a 16 x 2-bit or 32 x 1-bit synchronous RAM, or a 16x1-bit dual-port synchronous RAM.

The Virtex LUT can also provide a 16-bit shift register that is ideal for capturing high-speed or burst-mode data. This mode can also be used to store data in applications such as Digital Signal Processing.

Storage Elements

The storage elements in the Virtex slice can be configured either as edge-triggered D-type flip-flops or as level-sensitive latches. The D inputs can be driven either by the function generators within the slice or directly from slice inputs, bypassing the function generators.

In addition to Clock and Clock Enable signals, each Slice has synchronous set and reset signals (SR and BY). SR forces a storage element into the initialization state specified for it in the configuration. BY forces it into the opposite state. Alternatively, these signals can be configured to operate asynchronously. All of the control signals are independently invertible, and are shared by the two flip-flops within the slice.

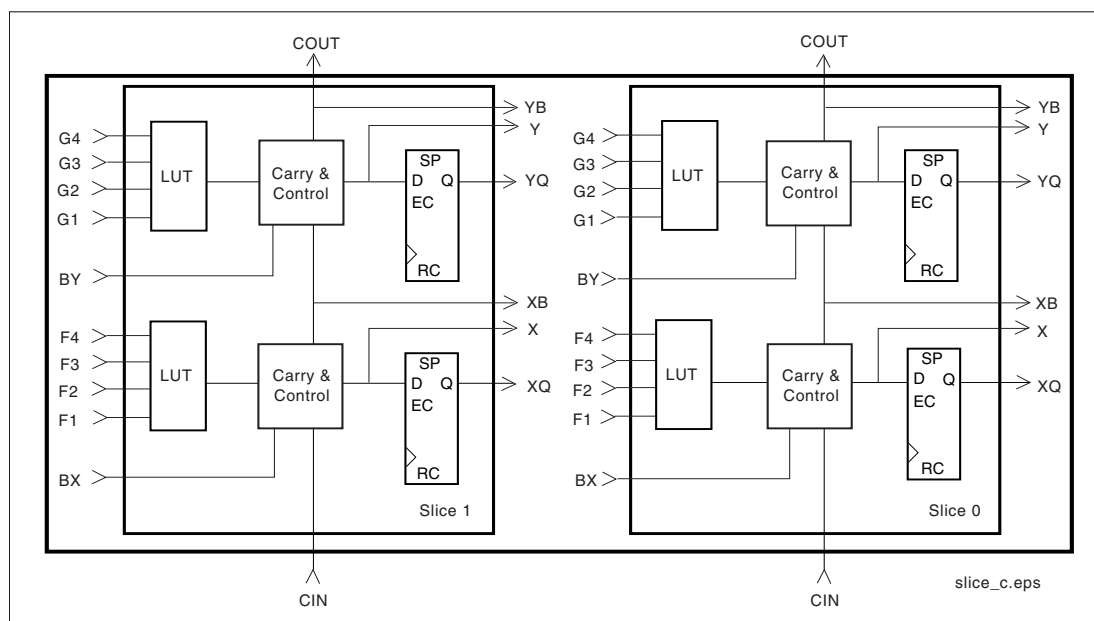


Figure 4: 2-Slice Virtex CLB

Four dedicated clock pads are provided, one adjacent to each of the global buffers. The input to the global buffer is

selected either from these pads or from signals in the general purpose routing.

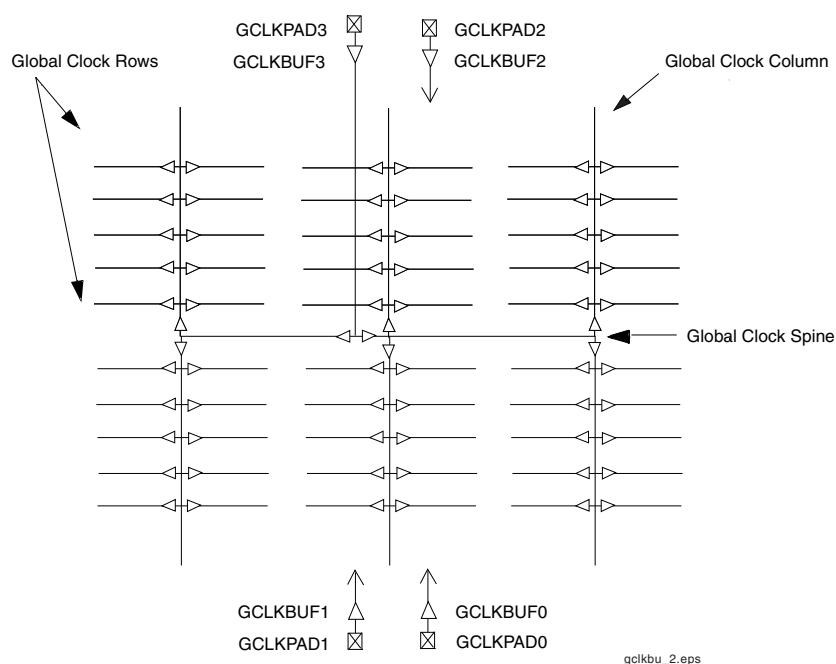


Figure 9: Global Clock Distribution Network

Delay-Locked Loop (DLL)

Associated with each global clock input buffer is a fully digital Delay-Locked Loop (DLL) that can eliminate skew between the clock input pad and internal clock-input pins throughout the device. Each DLL can drive two global clock networks. The DLL monitors the input clock and the distributed clock, and automatically adjusts a clock delay element. Clock edges reach internal flip-flops one to four clock periods after they arrive at the input. This closed-loop system effectively eliminates clock-distribution delay by ensuring that clock edges arrive at internal flip-flops in synchronism with clock edges arriving at the input.

In addition to eliminating clock-distribution delay, the DLL provides advanced control of multiple clock domains. The DLL provides four quadrature phases of the source clock, can double the clock, or divide the clock by 1.5, 2, 2.5, 3, 4, 5, 8, or 16.

The DLL also operates as a clock mirror. By driving the output from a DLL off-chip and then back on again, the DLL can be used to de-skew a board level clock among multiple Virtex devices.

In order to guarantee that the system clock is operating correctly prior to the FPGA starting up after configuration, the DLL can delay the completion of the configuration process until after it has achieved lock.

See **DLL Timing Parameters**, page 21 of Module 3, for frequency range information.

Boundary Scan

Virtex devices support all the mandatory boundary-scan instructions specified in the IEEE standard 1149.1. A Test Access Port (TAP) and registers are provided that implement the EXTEST, INTEST, SAMPLE/PRELOAD, BYPASS, IDCODE, USERCODE, and HIGHZ instructions. The TAP also supports two internal scan chains and configuration/readback of the device. The TAP uses dedicated package pins that always operate using LVTTTL. For TDO to operate using LVTTTL, the V_{CCO} for Bank 2 should be 3.3 V. Otherwise, TDO switches rail-to-rail between ground and V_{CCO} .

Boundary-scan operation is independent of individual IOB configurations, and unaffected by package type. All IOBs, including un-bonded ones, are treated as independent 3-state bidirectional pins in a single scan chain. Retention of the bidirectional test capability after configuration facilitates the testing of external interconnections, provided the user design or application is turned off.

Table 5 lists the boundary-scan instructions supported in Virtex FPGAs. Internal signals can be captured during EXTEST by connecting them to un-bonded or unused IOBs. They can also be connected to the unused outputs of IOBs defined as unidirectional input pins.

Before the device is configured, all instructions except USER1 and USER2 are available. After configuration, all instructions are available. During configuration, it is recommended that those operations using the boundary-scan register (SAMPLE/PRELOAD, INTEST, EXTEST) not be performed.

In addition to the test instructions outlined above, the boundary-scan circuitry can be used to configure the FPGA, and also to read back the configuration data.

Figure 10 is a diagram of the Virtex Series boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

Instruction Set

The Virtex Series boundary scan instruction set also includes instructions to configure the device and read back configuration data (CFG_IN, CFG_OUT, and JSTART). The complete instruction set is coded as shown in **Table 5**.

Data Registers

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out, and 3-State Control. Non-IOB pins have appropriate partial bit population if input-only or output-only. Each EXTEST CAPTURED-OR state captures all In, Out, and 3-state pins.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA supports up to two additional internal scan chains that can be specified using the BSCAN macro. The macro provides two user pins (SEL1 and SEL2) which are decoded by the USER1 and USER2 instructions respectively. For these instructions, two corresponding pins (TDO1 and TDO2) allow user scan data to be shifted out of TDO.

Likewise, there are individual clock pins (DRCK1 and DRCK2) for each user register. There is a common input pin (TDI) and shared output pins that represent the state of the TAP controller (RESET, SHIFT, and UPDATE).

Bit Sequence

The order within each IOB is: In, Out, 3-State. The input-only pins contribute only the In bit to the boundary scan I/O data register, while the output-only pins contribute all three bits.

From a cavity-up view of the chip (as shown in EPIC), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in **Figure 11**.

BSDL (Boundary Scan Description Language) files for Virtex Series devices are available on the Xilinx web site in the File Download area.

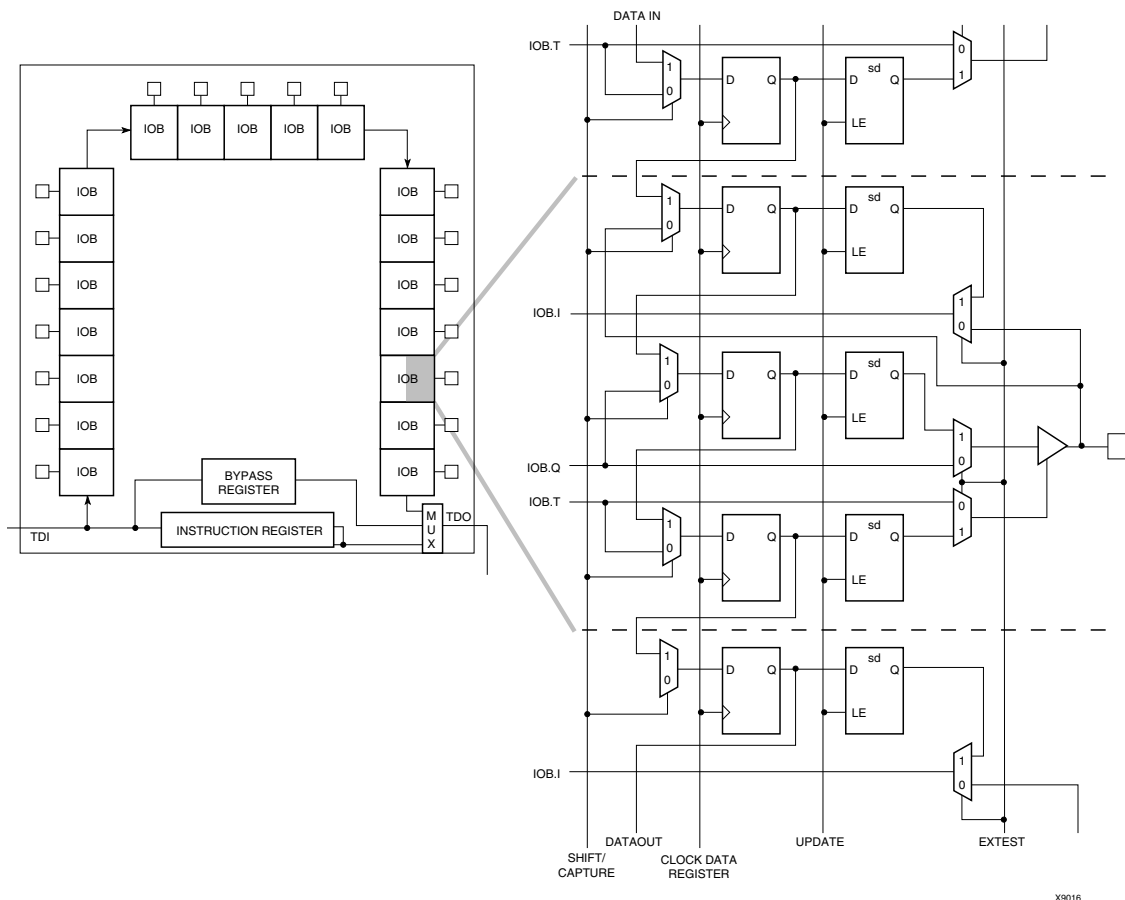


Figure 10: Virtex Series Boundary Scan Logic

Configuration

Virtex devices are configured by loading configuration data into the internal configuration memory. Some of the pins used for this are dedicated configuration pins, while others can be re-used as general purpose inputs and outputs once configuration is complete.

The following are dedicated pins:

- Mode pins (M2, M1, M0)
- Configuration clock pin (CCLK)
- $\overline{\text{PROGRAM}}$ pin
- DONE pin
- Boundary-scan pins (TDI, TDO, TMS, TCK)

Depending on the configuration mode chosen, CCLK can be an output generated by the FPGA, or it can be generated externally and provided to the FPGA as an input. The $\overline{\text{PROGRAM}}$ pin must be pulled High prior to reconfiguration.

Note that some configuration pins can act as outputs. For correct operation, these pins can require a V_{CCO} of 3.3 V to permit LVTTTL operation. All the pins affected are in banks 2 or 3. The configuration pins needed for SelectMap (CS, Write) are located in bank 1.

Table 7: Configuration Codes

Configuration Mode	M2	M1	M0	CCLK Direction	Data Width	Serial D _{out}	Configuration Pull-ups
Master-serial mode	0	0	0	Out	1	Yes	No
Boundary-scan mode	1	0	1	N/A	1	No	No
SelectMAP mode	1	1	0	In	8	No	No
Slave-serial mode	1	1	1	In	1	Yes	No
Master-serial mode	1	0	0	Out	1	Yes	Yes
Boundary-scan mode	0	0	1	N/A	1	No	Yes
SelectMAP mode	0	1	0	In	8	No	Yes
Slave-serial mode	0	1	1	In	1	Yes	Yes

Slave-Serial Mode

In slave-serial mode, the FPGA receives configuration data in bit-serial form from a serial PROM or other source of serial configuration data. The serial bitstream must be setup at the DIN input pin a short time before each rising edge of an externally generated CCLK.

For more information on serial PROMs, see the PROM data sheet at:

<http://www.xilinx.com/bvdocs/publications/ds026.pdf>.

Multiple FPGAs can be daisy-chained for configuration from a single source. After a particular FPGA has been configured, the data for the next device is routed to the DOUT pin. The data on the DOUT pin changes on the rising edge of CCLK.

The change of DOUT on the rising edge of CCLK differs from previous families, but does not cause a problem for

After Virtex devices are configured, unused IOBs function as 3-state OBUFTs with weak pull downs. For a more detailed description than that given below, see the XAPP138, Virtex Configuration and Readback.

Configuration Modes

Virtex supports the following four configuration modes.

- Slave-serial mode
- Master-serial mode
- SelectMAP mode
- Boundary-scan mode

The Configuration mode pins (M2, M1, M0) select among these configuration modes with the option in each case of having the IOB pins either pulled up or left floating prior to configuration. The selection codes are listed in Table 7.

Configuration through the boundary-scan port is always available, independent of the mode selection. Selecting the boundary-scan mode simply turns off the other modes. The three mode pins have internal pull-up resistors, and default to a logic High if left unconnected. However, it is recommended to drive the configuration mode pins externally.

mixed configuration chains. This change was made to improve serial configuration rates for Virtex-only chains.

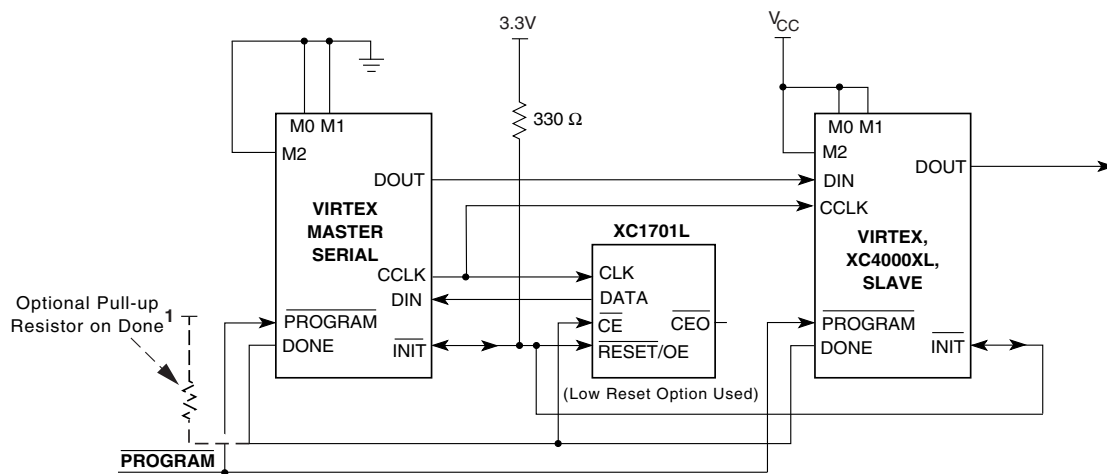
Figure 12 shows a full master/slave system. A Virtex device in slave-serial mode should be connected as shown in the third device from the left.

Slave-serial mode is selected by applying <111> or <011> to the mode pins (M2, M1, M0). A weak pull-up on the mode pins makes slave-serial the default mode if the pins are left unconnected. However, it is recommended to drive the configuration mode pins externally. Figure 13 shows slave-serial mode programming switching characteristics.

Table 8 provides more detail about the characteristics shown in Figure 13. Configuration must be delayed until the $\overline{\text{INIT}}$ pins of all daisy-chained FPGAs are High.

Table 8: Master/Slave Serial Mode Programming Switching

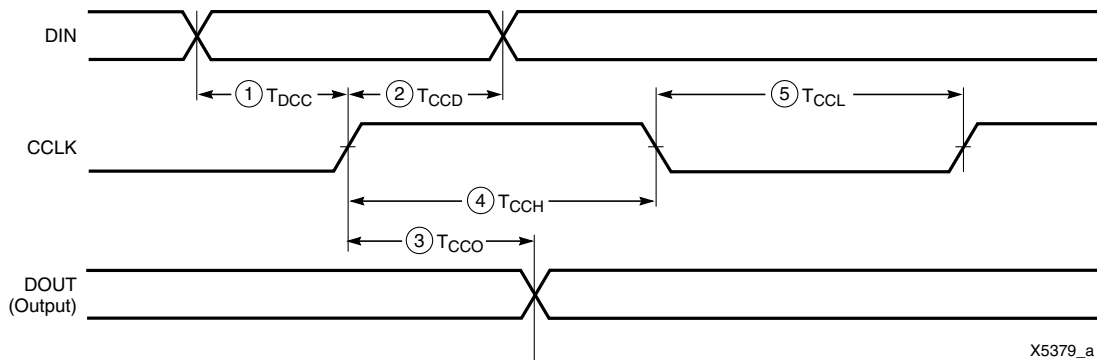
	Description	Figure References	Symbol	Values	Units
CCLK	DIN setup/hold, slave mode	1/2	T_{DCC}/T_{CCD}	5.0 / 0	ns, min
	DIN setup/hold, master mode	1/2	T_{DSCK}/T_{CKDS}	5.0 / 0	ns, min
	DOUT	3	T_{CCO}	12.0	ns, max
	High time	4	T_{CCH}	5.0	ns, min
	Low time	5	T_{CCL}	5.0	ns, min
	Maximum Frequency		F_{CC}	66	MHz, max
	Frequency Tolerance, master mode with respect to nominal			+45% -30%	



Note 1: If none of the Virtex FPGAs have been selected to drive DONE, an external pull-up resistor of 330 Ω should be added to the common DONE line. (For Spartan-XL devices, add a 4.7K Ω pull-up resistor.) This pull-up is not needed if the DriveDONE attribute is set. If used, DriveDONE should be selected only for the last device in the configuration chain.

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Figure 12: Master/Slave Serial Mode Circuit Diagram



X5379_a

Figure 13: Slave-Serial Mode Programming Switching Characteristics

Data Stream Format

Virtex devices are configured by sequentially loading frames of data. Table 11 lists the total number of bits required to configure each device. For more detailed information, see application note XAPP151 “Virtex Configuration Architecture Advanced Users Guide”.

Table 11: Virtex Bit-Stream Lengths

Device	# of Configuration Bits
XCV50	559,200
XCV100	781,216
XCV150	1,040,096
XCV200	1,335,840
XCV300	1,751,808
XCV400	2,546,048
XCV600	3,607,968
XCV800	4,715,616
XCV1000	6,127,744

Readback

The configuration data stored in the Virtex configuration memory can be readback for verification. Along with the configuration data it is possible to readback the contents all flip-flops/latches, LUTRAMs, and block RAMs. This capability is used for real-time debugging.

For more detailed information, see Application Note XAPP138: *Virtex FPGA Series Configuration and Readback*, available online at www.xilinx.com.

Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99	1.2	Updated package drawings and specs.
02/99	1.3	Update of package drawings, updated specifications.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, “0” hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T _{IJITCC} parameter, changed T _{OJIT} to T _{OPHASE} .
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036, 111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V _{CCO} in CS144 package on p.43.

Date	Version	Revision
01/00	1.9	Updated DLL Jitter Parameter table and waveforms, added Delay Measurement Methodology table for different I/O standards, changed buffered Hex line info and Input/Output Timing measurement notes.
03/00	2.0	New TBCKO values; corrected FG680 package connection drawing; new note about status of CCLK pin after configuration.
05/00	2.1	Modified “Pins not listed...” statement. Speed grade update to Final status.
05/00	2.2	Modified Table 18.
09/00	2.3	<ul style="list-style-type: none"> Added XCV400 values to table under Minimum Clock-to-Out for Virtex Devices. Corrected Units column in table under IOB Input Switching Characteristics. Added values to table under CLB SelectRAM Switching Characteristics.
10/00	2.4	<ul style="list-style-type: none"> Corrected Pinout information for devices in the BG256, BG432, and BG560 packages in Table 18. Corrected BG256 Pin Function Diagram.
04/01	2.5	<ul style="list-style-type: none"> Revised minimums for Global Clock Set-Up and Hold for LVTTTL Standard, with DLL. Updated SelectMAP Write Timing Characteristics values in Table 9. Converted file to modularized format. See the Virtex Data Sheet section.
07/19/01	2.6	<ul style="list-style-type: none"> Made minor edits to text under Configuration.
07/19/02	2.7	<ul style="list-style-type: none"> Made minor edit to Figure 16 and Figure 18.
09/10/02	2.8	<ul style="list-style-type: none"> Added clarifications in the Configuration, Boundary-Scan Mode, and Block SelectRAM sections. Revised Figure 17.
12/09/02	2.8.1	<ul style="list-style-type: none"> Added clarification in the Boundary Scan section. Corrected number of buffered Hex lines listed in General Purpose Routing section.
03/01/13	4.0	The products listed in this data sheet are obsolete. See XCN10016 for further information.

Virtex Data Sheet

The Virtex Data Sheet contains the following modules:

- DS003-1, Virtex 2.5V FPGAs:
Introduction and Ordering Information (Module 1)
- DS003-2, Virtex 2.5V FPGAs:
Functional Description (Module 2)
- DS003-3, Virtex 2.5V FPGAs:
DC and Switching Characteristics (Module 3)
- DS003-4, Virtex 2.5V FPGAs:
Pinout Tables (Module 4)

Virtex Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation net list. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Virtex devices unless otherwise noted.

IOB Input Switching Characteristics

Input delays associated with the pad are specified for LVTTTL levels. For other standards, adjust the delays with the values shown in , page 6.

Description	Device	Symbol	Speed Grade				Units
			Min	-6	-5	-4	
Propagation Delays							
Pad to I output, no delay	All	T _{IOPI}	0.39	0.8	0.9	1.0	ns, max
Pad to I output, with delay	XCV50	T _{IOPID}	0.8	1.5	1.7	1.9	ns, max
	XCV100		0.8	1.5	1.7	1.9	ns, max
	XCV150		0.8	1.5	1.7	1.9	ns, max
	XCV200		0.8	1.5	1.7	1.9	ns, max
	XCV300		0.8	1.5	1.7	1.9	ns, max
	XCV400		0.9	1.8	2.0	2.3	ns, max
	XCV600		0.9	1.8	2.0	2.3	ns, max
	XCV800		1.1	2.1	2.4	2.7	ns, max
	XCV1000		1.1	2.1	2.4	2.7	ns, max
Pad to output IQ via transparent latch, no delay	All	T _{IOPLI}	0.8	1.6	1.8	2.0	ns, max
Pad to output IQ via transparent latch, with delay	XCV50	T _{IOPLID}	1.9	3.7	4.2	4.8	ns, max
	XCV100		1.9	3.7	4.2	4.8	ns, max
	XCV150		2.0	3.9	4.3	4.9	ns, max
	XCV200		2.0	4.0	4.4	5.1	ns, max
	XCV300		2.0	4.0	4.4	5.1	ns, max
	XCV400		2.1	4.1	4.6	5.3	ns, max
	XCV600		2.1	4.2	4.7	5.4	ns, max
	XCV800		2.2	4.4	4.9	5.6	ns, max
	XCV1000		2.3	4.5	5.1	5.8	ns, max
Sequential Delays							
Clock CLK	All						
Minimum Pulse Width, High		T _{CH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low		T _{CL}	0.8	1.5	1.7	2.0	ns, min
Clock CLK to output IQ		T _{IOCKIQ}	0.2	0.7	0.7	0.8	ns, max

Calculation of $T_{i\text{oop}}$ as a Function of Capacitance

$T_{i\text{oop}}$ is the propagation delay from the O Input of the IOB to the pad. The values for $T_{i\text{oop}}$ were based on the standard capacitive load (C_{sl}) for each I/O standard as listed in Table 2.

Table 2: Constants for Calculating $T_{i\text{oop}}$

Standard	Csl (pF)	fl (ns/pF)
LVTTL Fast Slew Rate, 2mA drive	35	0.41
LVTTL Fast Slew Rate, 4mA drive	35	0.20
LVTTL Fast Slew Rate, 6mA drive	35	0.13
LVTTL Fast Slew Rate, 8mA drive	35	0.079
LVTTL Fast Slew Rate, 12mA drive	35	0.044
LVTTL Fast Slew Rate, 16mA drive	35	0.043
LVTTL Fast Slew Rate, 24mA drive	35	0.033
LVTTL Slow Slew Rate, 2mA drive	35	0.41
LVTTL Slow Slew Rate, 4mA drive	35	0.20
LVTTL Slow Slew Rate, 6mA drive	35	0.100
LVTTL Slow Slew Rate, 8mA drive	35	0.086
LVTTL Slow Slew Rate, 12mA drive	35	0.058
LVTTL Slow Slew Rate, 16mA drive	35	0.050
LVTTL Slow Slew Rate, 24mA drive	35	0.048
LVCMS2	35	0.041
PCI 33MHz 5V	50	0.050
PCI 33MHZ 3.3 V	10	0.050
PCI 66 MHz 3.3 V	10	0.033
GTL	0	0.014
GTL+	0	0.017
HSTL Class I	20	0.022
HSTL Class III	20	0.016
HSTL Class IV	20	0.014
SSTL2 Class I	30	0.028
SSTL2 Class II	30	0.016
SSTL3 Class I	30	0.029
SSTL3 Class II	30	0.016
CTT	20	0.035
AGP	10	0.037

Notes:

1. I/O parameter measurements are made with the capacitance values shown above. See Application Note XAPP133 on www.xilinx.com for appropriate terminations.
2. I/O standard measurements are reflected in the IBIS model information except where the IBIS format precludes it.

For other capacitive loads, use the formulas below to calculate the corresponding $T_{i\text{oop}}$.

$$T_{i\text{oop}} = T_{i\text{oop}} + T_{\text{opadjust}} + (C_{\text{load}} - C_{sl}) * fl$$

Where:

T_{opadjust} is reported above in the Output Delay Adjustment section.

C_{load} is the capacitive load for the design.

Table 3: Delay Measurement Methodology

Standard	V_L (1)	V_H (1)	Meas. Point	V_{REF} Typ (2)
LVTTL	0	3	1.4	-
LVCMS2	0	2.5	1.125	-
PCI33_5	Per PCI Spec			-
PCI33_3	Per PCI Spec			-
PCI66_3	Per PCI Spec			-
GTL	$V_{REF} - 0.2$	$V_{REF} + 0.2$	V_{REF}	0.80
GTL+	$V_{REF} - 0.2$	$V_{REF} + 0.2$	V_{REF}	1.0
HSTL Class I	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.75
HSTL Class III	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.90
HSTL Class IV	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.90
SSTL3 I & II	$V_{REF} - 1.0$	$V_{REF} + 1.0$	V_{REF}	1.5
SSTL2 I & II	$V_{REF} - 0.75$	$V_{REF} + 0.75$	V_{REF}	1.25
CTT	$V_{REF} - 0.2$	$V_{REF} + 0.2$	V_{REF}	1.5
AGP	$V_{REF} - (0.2 \times V_{CCO})$	$V_{REF} + (0.2 \times V_{CCO})$	V_{REF}	Per AGP Spec

Notes:

1. Input waveform switches between V_L and V_H .
2. Measurements are made at V_{REF} (Typ), Maximum, and Minimum. Worst-case values are reported.
3. I/O parameter measurements are made with the capacitance values shown in Table 2. See Application Note XAPP133 on www.xilinx.com for appropriate terminations.
4. I/O standard measurements are reflected in the IBIS model information except where the IBIS format precludes it.

I/O Standard Global Clock Input Adjustments

Description	Symbol	Standard ⁽¹⁾	Speed Grade				Units
			Min	-6	-5	-4	
Data Input Delay Adjustments							
Standard-specific global clock input delay adjustments	T _{GPLVTTL}	LVTTL	0	0	0	0	ns, max
	T _{GPLVCMOS2}	LVC MOS2	−0.02	−0.04	−0.04	−0.05	ns, max
	T _{GP PCI33_3}	PCI, 33 MHz, 3.3 V	−0.05	−0.11	−0.12	−0.14	ns, max
	T _{GP PCI33_5}	PCI, 33 MHz, 5.0 V	0.13	0.25	0.28	0.33	ns, max
	T _{GP PCI66_3}	PCI, 66 MHz, 3.3 V	−0.05	−0.11	−0.12	−0.14	ns, max
	T _{GPGTL}	GTL	0.7	0.8	0.9	0.9	ns, max
	T _{GPGTLP}	GTL+	0.7	0.8	0.8	0.8	ns, max
	T _{GPHSTL}	HSTL	0.7	0.7	0.7	0.7	ns, max
	T _{GPSSTL2}	SSTL2	0.6	0.52	0.51	0.50	ns, max
	T _{GPSSTL3}	SSTL3	0.6	0.6	0.55	0.54	ns, max
	T _{GPCTT}	CTT	0.7	0.7	0.7	0.7	ns, max
	T _{GPAGP}	AGP	0.6	0.54	0.53	0.52	ns, max

Notes:

1. Input timing for GPLVTTL is measured at 1.4 V. For other I/O standards, see [Table 3](#).

CLB Switching Characteristics

Delays originating at F/G inputs vary slightly according to the input used. The values listed below are worst-case. Precise values are provided by the timing analyzer.

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Combinatorial Delays						
4-input function: F/G inputs to X/Y outputs	T _{ILO}	0.29	0.6	0.7	0.8	ns, max
5-input function: F/G inputs to F5 output	T _{IF5}	0.32	0.7	0.8	0.9	ns, max
5-input function: F/G inputs to X output	T _{IF5X}	0.36	0.8	0.8	1.0	ns, max
6-input function: F/G inputs to Y output via F6 MUX	T _{IF6Y}	0.44	0.9	1.0	1.2	ns, max
6-input function: F5IN input to Y output	T _{F5INY}	0.17	0.32	0.36	0.42	ns, max
Incremental delay routing through transparent latch to XQ/YQ outputs	T _{IFNCTL}	0.31	0.7	0.7	0.8	ns, max
BY input to YB output	T _{BYYB}	0.27	0.53	0.6	0.7	ns, max
Sequential Delays						
FF Clock CLK to XQ/YQ outputs	T _{CKO}	0.54	1.1	1.2	1.4	ns, max
Latch Clock CLK to XQ/YQ outputs	T _{CKLO}	0.6	1.2	1.4	1.6	ns, max
Setup and Hold Times before/after Clock CLK ⁽¹⁾	Setup Time / Hold Time					
4-input function: F/G Inputs	T _{ICK} /T _{CKI}	0.6 / 0	1.2 / 0	1.4 / 0	1.5 / 0	ns, min
5-input function: F/G inputs	T _{IF5CK} /T _{CKIF5}	0.7 / 0	1.3 / 0	1.5 / 0	1.7 / 0	ns, min
6-input function: F5IN input	T _{F5INCK} /T _{CKF5IN}	0.46 / 0	1.0 / 0	1.1 / 0	1.2 / 0	ns, min
6-input function: F/G inputs via F6 MUX	T _{IF6CK} /T _{CKIF6}	0.8 / 0	1.5 / 0	1.7 / 0	1.9 / 0	ns, min
BX/BY inputs	T _{DICK} /T _{CKDI}	0.30 / 0	0.6 / 0	0.7 / 0	0.8 / 0	ns, min
CE input	T _{CECK} /T _{CKCE}	0.37 / 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, min
SR/BY inputs (synchronous)	T _{RCK} T _{CKR}	0.33 / 0	0.7 / 0	0.8 / 0	0.9 / 0	ns, min
Clock CLK						
Minimum Pulse Width, High	T _{CH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T _{CL}	0.8	1.5	1.7	2.0	ns, min
Set/Reset						
Minimum Pulse Width, SR/BY inputs	T _{RPW}	1.3	2.5	2.8	3.3	ns, min
Delay from SR/BY inputs to XQ/YQ outputs (asynchronous)	T _{RQ}	0.54	1.1	1.3	1.4	ns, max
Delay from GSR to XQ/YQ outputs	T _{IOGSRQ}	4.9	9.7	10.9	12.5	ns, max
Toggle Frequency (MHz) (for export control)	F _{TOG} (MHz)	625	333	294	250	MHz

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

CLB Arithmetic Switching Characteristics

Setup times not listed explicitly can be approximated by decreasing the combinatorial delays by the setup time adjustment listed. Precise values are provided by the timing analyzer.

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Combinatorial Delays						
F operand inputs to X via XOR	T _{OPX}	0.37	0.8	0.9	1.0	ns, max
F operand input to XB output	T _{OPXB}	0.54	1.1	1.3	1.4	ns, max
F operand input to Y via XOR	T _{OPY}	0.8	1.5	1.7	2.0	ns, max
F operand input to YB output	T _{OPYB}	0.8	1.5	1.7	2.0	ns, max
F operand input to COUT output	T _{OPCYF}	0.6	1.2	1.3	1.5	ns, max
G operand inputs to Y via XOR	T _{OPGY}	0.46	1.0	1.1	1.2	ns, max
G operand input to YB output	T _{OPGYB}	0.8	1.6	1.8	2.1	ns, max
G operand input to COUT output	T _{OPCYG}	0.7	1.3	1.4	1.6	ns, max
BX initialization input to COUT	T _{BXCY}	0.41	0.9	1.0	1.1	ns, max
CIN input to X output via XOR	T _{CINX}	0.21	0.41	0.46	0.53	ns, max
CIN input to XB	T _{CINXB}	0.02	0.04	0.05	0.06	ns, max
CIN input to Y via XOR	T _{CINY}	0.23	0.46	0.52	0.6	ns, max
CIN input to YB	T _{CINYB}	0.23	0.45	0.51	0.6	ns, max
CIN input to COUT output	T _{BYP}	0.05	0.09	0.10	0.11	ns, max
Multiplier Operation						
F1/2 operand inputs to XB output via AND	T _{FANDXB}	0.18	0.36	0.40	0.46	ns, max
F1/2 operand inputs to YB output via AND	T _{FANDYB}	0.40	0.8	0.9	1.1	ns, max
F1/2 operand inputs to COUT output via AND	T _{FANDCY}	0.22	0.43	0.48	0.6	ns, max
G1/2 operand inputs to YB output via AND	T _{GANDYB}	0.25	0.50	0.6	0.7	ns, max
G1/2 operand inputs to COUT output via AND	T _{GANDCY}	0.07	0.13	0.15	0.17	ns, max
Setup and Hold Times before/after Clock CLK ⁽¹⁾	Setup Time / Hold Time					
CIN input to FFX	T _{CCKX} /T _{CKCX}	0.50 / 0	1.0 / 0	1.2 / 0	1.3 / 0	ns, min
CIN input to FFY	T _{CCKY} /T _{CKCY}	0.53 / 0	1.1 / 0	1.2 / 0	1.4 / 0	ns, min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

CLB SelectRAM Switching Characteristics

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Sequential Delays						
Clock CLK to X/Y outputs (WE active) 16 x 1 mode	T _{SHCKO16}	1.2	2.3	2.6	3.0	ns, max
Clock CLK to X/Y outputs (WE active) 32 x 1 mode	T _{SHCKO32}	1.2	2.7	3.1	3.5	ns, max
Shift-Register Mode						
Clock CLK to X/Y outputs	T _{REG}	1.2	3.7	4.1	4.7	ns, max
Setup and Hold Times before/after Clock CLK ⁽¹⁾	Setup Time / Hold Time					
F/G address inputs	T _{AS} /T _{AH}	0.25 / 0	0.5 / 0	0.6 / 0	0.7 / 0	ns, min
BX/BY data inputs (DIN)	T _{DS} /T _{DH}	0.34 / 0	0.7 / 0	0.8 / 0	0.9 / 0	ns, min
CE input (WE)	T _{WS} /T _{WH}	0.38 / 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, min
Shift-Register Mode						
BX/BY data inputs (DIN)	T _{SHDICK}	0.34	0.7	0.8	0.9	ns, min
CE input (WS)	T _{SHCECK}	0.38	0.8	0.9	1.0	ns, min
Clock CLK						
Minimum Pulse Width, High	T _{WPH}	1.2	2.4	2.7	3.1	ns, min
Minimum Pulse Width, Low	T _{WPL}	1.2	2.4	2.7	3.1	ns, min
Minimum clock period to meet address write cycle time	T _{WC}	2.4	4.8	5.4	6.2	ns, min
Shift-Register Mode						
Minimum Pulse Width, High	T _{SRPH}	1.2	2.4	2.7	3.1	ns, min
Minimum Pulse Width, Low	T _{SRPL}	1.2	2.4	2.7	3.1	ns, min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

Virtex Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Listed below are representative values for typical pin locations and normal clock loading. Values are expressed in nanoseconds unless otherwise noted.

Global Clock Input to Output Delay for LVTTL, 12 mA, Fast Slew Rate, *with* DLL

Description	Symbol	Device	Speed Grade				Units
			Min	-6	-5	-4	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, <i>with</i> DLL. For data <i>output</i> with different standards, adjust delays with the values shown in Output Delay Adjustments.	T _{ICKOFDLL}	XCV50	1.0	3.1	3.3	3.6	ns, max
		XCV100	1.0	3.1	3.3	3.6	ns, max
		XCV150	1.0	3.1	3.3	3.6	ns, max
		XCV200	1.0	3.1	3.3	3.6	ns, max
		XCV300	1.0	3.1	3.3	3.6	ns, max
		XCV400	1.0	3.1	3.3	3.6	ns, max
		XCV600	1.0	3.1	3.3	3.6	ns, max
		XCV800	1.0	3.1	3.3	3.6	ns, max
		XCV1000	1.0	3.1	3.3	3.6	ns, max

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see [Table 2](#) and [Table 3](#).
3. DLL output jitter is already included in the timing calculation.

Global Clock Input-to-Output Delay for LVTTL, 12 mA, Fast Slew Rate, *without* DLL

Description	Symbol	Device	Speed Grade				Units
			Min	-6	-5	-4	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, <i>without</i> DLL. For data <i>output</i> with different standards, adjust delays with the values shown in Input and Output Delay Adjustments. For I/O standards requiring V _{REF} such as GTL, GTL+, SSTL, HSTL, CTT, and AGO, an additional 600 ps must be added.	T _{ICKOF}	XCV50	1.5	4.6	5.1	5.7	ns, max
		XCV100	1.5	4.6	5.1	5.7	ns, max
		XCV150	1.5	4.7	5.2	5.8	ns, max
		XCV200	1.5	4.7	5.2	5.8	ns, max
		XCV300	1.5	4.7	5.2	5.9	ns, max
		XCV400	1.5	4.8	5.3	6.0	ns, max
		XCV600	1.6	4.9	5.4	6.0	ns, max
		XCV800	1.6	4.9	5.5	6.2	ns, max
		XCV1000	1.7	5.0	5.6	6.3	ns, max

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see [Table 2](#) and [Table 3](#).

Global Clock Set-Up and Hold for LVTTL Standard, *without* DLL

Description	Symbol	Device	Speed Grade				Units
			Min	-6	-5	-4	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVTTL Standard. ⁽²⁾ For data input with different standards, adjust the setup time delay by the values shown in Input Delay Adjustments.							
Full Delay Global Clock and IFF, without DLL	T _{PSFD} /T _{PHFD}	XCV50	0.6 / 0	2.3 / 0	2.6 / 0	2.9 / 0	ns, min
		XCV100	0.6 / 0	2.3 / 0	2.6 / 0	3.0 / 0	ns, min
		XCV150	0.6 / 0	2.4 / 0	2.7 / 0	3.1 / 0	ns, min
		XCV200	0.7 / 0	2.5 / 0	2.8 / 0	3.2 / 0	ns, min
		XCV300	0.7 / 0	2.5 / 0	2.8 / 0	3.2 / 0	ns, min
		XCV400	0.7 / 0	2.6 / 0	2.9 / 0	3.3 / 0	ns, min
		XCV600	0.7 / 0	2.6 / 0	2.9 / 0	3.3 / 0	ns, min
		XCV800	0.7 / 0	2.7 / 0	3.1 / 0	3.5 / 0	ns, min
		XCV1000	0.7 / 0	2.8 / 0	3.1 / 0	3.6 / 0	ns, min

IFF = Input Flip-Flop or Latch

Notes: Notes:

1. Set-up time is measured relative to the Global Clock input signal with the fastest route and the lightest load. Hold time is measured relative to the Global Clock input signal with the slowest route and heaviest load.
2. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

Date	Version	Revision
01/00	1.9	Updated DLL Jitter Parameter table and waveforms, added Delay Measurement Methodology table for different I/O standards, changed buffered Hex line info and Input/Output Timing measurement notes.
03/00	2.0	New TBCKO values; corrected FG680 package connection drawing; new note about status of CCLK pin after configuration.
05/00	2.1	Modified "Pins not listed..." statement. Speed grade update to Final status.
05/00	2.2	Modified Table 18.
09/00	2.3	<ul style="list-style-type: none"> Added XCV400 values to table under Minimum Clock-to-Out for Virtex Devices. Corrected Units column in table under IOB Input Switching Characteristics. Added values to table under CLB SelectRAM Switching Characteristics.
10/00	2.4	<ul style="list-style-type: none"> Corrected Pinout information for devices in the BG256, BG432, and BG560 packages in Table 18. Corrected BG256 Pin Function Diagram.
04/02/01	2.5	<ul style="list-style-type: none"> Revised minimums for Global Clock Set-Up and Hold for LVTTTL Standard, with DLL. Converted file to modularized format. See the Virtex Data Sheet section.
04/19/01	2.6	<ul style="list-style-type: none"> Clarified TIOCKP and TIOCKON IOB Output Switching Characteristics descriptors.
07/19/01	2.7	<ul style="list-style-type: none"> Under Absolute Maximum Ratings, changed (T_{SOL}) to 220 °C.
07/26/01	2.8	<ul style="list-style-type: none"> Removed T_{SOL} parameter and added footnote to Absolute Maximum Ratings table.
10/29/01	2.9	<ul style="list-style-type: none"> Updated the speed grade designations used in data sheets, and added Table 1, which shows the current speed grade designation for each device.
02/01/02	3.0	<ul style="list-style-type: none"> Added footnote to DC Input and Output Levels table.
07/19/02	3.1	<ul style="list-style-type: none"> Removed mention of MIL-M-38510/605 specification. Added link to xapp158 from the Power-On Power Supply Requirements section.
09/10/02	3.2	<ul style="list-style-type: none"> Added Clock CLK to IOB Input Switching Characteristics and IOB Output Switching Characteristics.
03/01/13	4.0	The products listed in this data sheet are obsolete. See XCN10016 for further information.

Virtex Data Sheet

The Virtex Data Sheet contains the following modules:

- DS003-1, Virtex 2.5V FPGAs:
Introduction and Ordering Information (Module 1)
- DS003-2, Virtex 2.5V FPGAs:
Functional Description (Module 2)
- DS003-3, Virtex 2.5V FPGAs:
DC and Switching Characteristics (Module 3)
- DS003-4, Virtex 2.5V FPGAs:
Pinout Tables (Module 4)



Virtex™ 2.5 V Field Programmable Gate Arrays

DS003-4 (v4.0) March 1, 2013

Production Product Specification

Virtex Pin Definitions

Table 1: Special Purpose Pins

Pin Name	Dedicated Pin	Direction	Description
GCK0, GCK1, GCK2, GCK3	Yes	Input	Clock input pins that connect to Global Clock Buffers. These pins become user inputs when not needed for clocks.
M0, M1, M2	Yes	Input	Mode pins are used to specify the configuration mode.
CCLK	Yes	Input or Output	The configuration Clock I/O pin: it is an input for SelectMAP and slave-serial modes, and output in master-serial mode. After configuration, it is input only, logic level = Don't Care.
PROGRAM	Yes	Input	Initiates a configuration sequence when asserted Low.
DONE	Yes	Bidirectional	Indicates that configuration loading is complete, and that the start-up sequence is in progress. The output can be open drain.
INIT	No	Bidirectional (Open-drain)	When Low, indicates that the configuration memory is being cleared. The pin becomes a user I/O after configuration.
BUSY/ DOUT	No	Output	In SelectMAP mode, BUSY controls the rate at which configuration data is loaded. The pin becomes a user I/O after configuration unless the SelectMAP port is retained. In bit-serial modes, DOUT provides header information to downstream devices in a daisy-chain. The pin becomes a user I/O after configuration.
D0/DIN, D1, D2, D3, D4, D5, D6, D7	No	Input or Output	In SelectMAP mode, D0 - D7 are configuration data pins. These pins become user I/Os after configuration unless the SelectMAP port is retained. In bit-serial modes, DIN is the single data input. This pin becomes a user I/O after configuration.
WRITE	No	Input	In SelectMAP mode, the active-low Write Enable signal. The pin becomes a user I/O after configuration unless the SelectMAP port is retained.
CS	No	Input	In SelectMAP mode, the active-low Chip Select signal. The pin becomes a user I/O after configuration unless the SelectMAP port is retained.
TDI, TDO, TMS, TCK	Yes	Mixed	Boundary-scan Test-Access-Port pins, as defined in IEEE 1149.1.
DXN, DXP	Yes	N/A	Temperature-sensing diode pins. (Anode: DXP, cathode: DXN)
V _{CCINT}	Yes	Input	Power-supply pins for the internal core logic.
V _{CCO}	Yes	Input	Power-supply pins for the output drivers (subject to banking rules)
V _{REF}	No	Input	Input threshold voltage pins. Become user I/Os when an external threshold voltage is not needed (subject to banking rules).
GND	Yes	Input	Ground

Table 4: Virtex Pinout Tables (Fine-Pitch BGA)

Pin Name	Device	FG256	FG456	FG676	FG680
GCK0	All	N8	W12	AA14	AW19
GCK1	All	R8	Y11	AB13	AU22
GCK2	All	C9	A11	C13	D21
GCK3	All	B8	C11	E13	A20
M0	All	N3	AB2	AD4	AT37
M1	All	P2	U5	W7	AU38
M2	All	R3	Y4	AB6	AT35
CCLK	All	D15	B22	D24	E4
PROGRAM	All	P15	W20	AA22	AT5
DONE	All	R14	Y19	AB21	AU5
INIT	All	N15	V19	Y21	AU2
BUSY/DOUT	All	C15	C21	E23	E3
D0/DIN	All	D14	D20	F22	C2
D1	All	E16	H22	K24	P4
D2	All	F15	H20	K22	P3
D3	All	G16	K20	M22	R1
D4	All	J16	N22	R24	AD3
D5	All	M16	R21	U23	AG2
D6	All	N16	T22	V24	AH1
D7	All	N14	Y21	AB23	AR4
WRITE	All	C13	A20	C22	B4
CS	All	B13	C19	E21	D5
TDI	All	A15	B20	D22	B3
TDO	All	B14	A21	C23	C4
TMS	All	D3	D3	F5	E36
TCK	All	C4	C4	E6	C36
DXN	All	R4	Y5	AB7	AV37
DXP	All	P4	V6	Y8	AU35

Pinout Diagrams

The following diagrams, **CS144 Pin Function Diagram**, page 17 through **FG680 Pin Function Diagram**, page 27, illustrate the locations of special-purpose pins on Virtex FPGAs. Table 5 lists the symbols used in these diagrams. The diagrams also show I/O-bank boundaries.

Table 5: Pinout Diagram Symbols

Symbol	Pin Function
*	General I/O
*	Device-dependent general I/O, n/c on smaller devices
V	V _{CCINT}
v	Device-dependent V _{CCINT} , n/c on smaller devices
O	V _{CCO}
R	V _{REF}
r	Device-dependent V _{REF} , remains I/O on smaller devices
G	Ground
Ø, 1, 2, 3	Global Clocks

Table 5: Pinout Diagram Symbols (Continued)

Symbol	Pin Function
⑩, ①, ②	M0, M1, M2
⑩, ①, ②, ③, ④, ⑤, ⑥, ⑦	D0/DIN, D1, D2, D3, D4, D5, D6, D7
B	DOUT/BUSY
D	DONE
P	PROGRAM
I	INIT
K	CCLK
W	WRITE
S	CS
T	Boundary-scan Test Access Port
+	Temperature diode, anode
–	Temperature diode, cathode
n	No connect

CS144 Pin Function Diagram

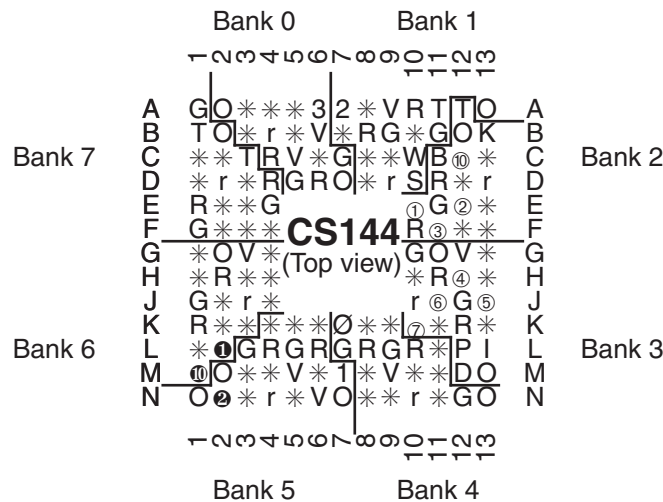


Figure 1: CS144 Pin Function Diagram